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Embedded - System On Chip (SoC): The Heart of Modern Embedded Systems

Embedded - System On Chip (SoC) refers to an integrated circuit that consolidates all the essential components of a computer system into a single chip. This includes a microprocessor, memory, and other peripherals, all packed into one compact and efficient package. SoCs are designed to provide a complete computing solution, optimizing both space and power consumption, making them ideal for a wide range of embedded applications.

What are Embedded - System On Chip (SoC)?

System On Chip (SoC) integrates multiple functions of a computer or electronic system onto a single chip. Unlike traditional multi-chip solutions, SoCs combine a central

Details

Product Status	Active
Architecture	MCU, FPGA
Core Processor	Quad ARM® Cortex®-A53 MPCore™ with CoreSight™, Dual ARM® Cortex™-R5 with CoreSight™, ARM Mali™-400 MP2
Flash Size	-
RAM Size	256KB
Peripherals	DMA, WDT
Connectivity	CANbus, EBI/EMI, Ethernet, I²C, MMC/SD/SDIO, SPI, UART/USART, USB OTG
Speed	533MHz, 600MHz, 1.3GHz
Primary Attributes	Zynq®UltraScale+™ FPGA, 747K+ Logic Cells
Operating Temperature	0°C ~ 100°C (TJ)
Package / Case	900-BBGA, FCBGA
Supplier Device Package	900-FCBGA (31x31)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xczu15eg-2ffvc900e

Recommended Operating Conditions

Table 2: Recommended Operating Conditions⁽¹⁾⁽²⁾

Symbol	Description	Min	Typ	Max	Units
Processor System					
V _{CC_PSINTFP} ⁽³⁾	PS full-power domain supply voltage.	0.808	0.850	0.892	V
	For -1LI and -2LE ($V_{CCINT} = 0.72V$) devices: PS full-power domain supply voltage.	0.808	0.850	0.892	V
	For -3E devices: PS full-power domain supply voltage.	0.873	0.900	0.927	V
V _{CC_PSINTLP}	PS low-power domain supply voltage.	0.808	0.850	0.892	V
	For -1LI and -2LE ($V_{CCINT} = 0.72V$) devices: PS low-power domain supply voltage.	0.808	0.850	0.892	V
	For -3E devices: PS low-power domain supply voltage.	0.873	0.900	0.927	V
V _{CC_PSAUX}	PS auxiliary supply voltage.	1.710	1.800	1.890	V
V _{CC_PSINTFP_DDR} ⁽³⁾	PS DDR controller and PHY supply voltage.	0.808	0.850	0.892	V
	For -1LI and -2LE ($V_{CCINT} = 0.72V$) devices: PS DDR controller and PHY supply voltage.	0.808	0.850	0.892	V
	For -3E devices: PS DDR controller and PHY supply voltage.	0.873	0.900	0.927	V
V _{CC_PSADC}	PS SYSMON ADC supply voltage relative to GND_PSADC.	1.710	1.800	1.890	V
V _{CC_PSPLL}	PS PLL supply voltage.	1.164	1.200	1.236	V
V _{PS_MGTRAVCC}	PS-GTR supply voltage.	0.825	0.850	0.875	V
V _{PS_MGTRAVTT}	PS-GTR termination voltage.	1.746	1.800	1.854	V
V _{CCO_PSDDR} ⁽⁴⁾	PS DDR I/O supply voltage.	1.06	–	1.575	V
V _{CCO_PSDDR_PLL}	PS DDR PLL supply voltage.	1.710	1.800	1.890	V
V _{CCO_PSIO} ⁽⁵⁾	PS I/O supply.	1.710	–	3.465	V
V _{PSIN}	PS I/O input voltage.	-0.200	–	$V_{CCO_PSIO} + 0.200$	V
	PS DDR I/O input voltage.	-0.200	–	$V_{CCO_PSDDR} + 0.200$	
V _{CC_PSBATT} ⁽⁶⁾	PS battery-backed RAM and battery-backed real-time clock (RTC) supply voltage.	1.200	–	1.500	V
Programmable Logic					
V _{CCINT}	PL internal supply voltage.	0.825	0.850	0.876	V
	For -1LI and -2LE ($V_{CCINT} = 0.72V$) devices: PL internal supply voltage.	0.698	0.720	0.742	V
	For -3E devices: PL internal supply voltage.	0.873	0.900	0.927	V
V _{CCINT_IO} ⁽⁷⁾	PL internal supply voltage for the I/O banks.	0.825	0.850	0.876	V
	For -1LI and -2LE ($V_{CCINT} = 0.72V$) devices: PL internal supply voltage for the I/O banks.	0.825	0.850	0.876	V
	For -3E devices: PL internal supply voltage for the I/O banks.	0.873	0.900	0.927	V
V _{CCBRAM}	Block RAM supply voltage.	0.825	0.850	0.876	V
	For -3E devices: block RAM supply voltage.	0.873	0.900	0.927	V
V _{CCAUX}	Auxiliary supply voltage.	1.746	1.800	1.854	V

Table 11: Power Supply Ramp Time (Cont'd)

Symbol	Description	Min	Max	Units
T _{VCCO_PSDDR}	Ramp time from GND to 95% of V _{CCO_PSDDR} .	0.2	40	ms
T _{VCC_PSDDR_PLL}	Ramp time from GND to 95% of V _{CC_PSDDR_PLL} .	0.2	40	ms
T _{VCCO_PSIO}	Ramp time from GND to 95% of V _{CCO_PSIO} .	0.2	40	ms

DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at a minimum V_{CCO} with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

PS I/O Levels

Table 12: PS MIO and CONFIG DC Input and Output Levels⁽¹⁾

I/O Standard	V _{IL}		V _{IH}		V _{OL}	V _{OH}	I _{OL}	I _{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
LVCMOS33	-0.300	0.800	2.000	V _{CCO_PSIO}	0.40	2.40	12	-12
LVCMOS25	-0.300	0.700	1.700	V _{CCO_PSIO} + 0.30	0.70	1.70	12	-12
LVCMOS18	-0.300	35% V _{CCO_PSIO}	65% V _{CCO_PSIO}	V _{CCO_PSIO} + 0.30	0.45	V _{CCO_PSIO} - 0.45	12	-12

Notes:

- Tested according to relevant specifications.

Table 13: PS DDR DC Input and Output Levels⁽¹⁾

DDR Standard	V _{IL}		V _{IH}		V _{OL} ⁽²⁾		V _{OH} ⁽²⁾		I _{OL}	I _{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA		
DDR4	0.000	V _{REF} - 0.100	V _{REF} + 0.100	V _{CCO_PSDDR}	0.8 x V _{CCO_PSDDR} - 0.150	0.8 x V _{CCO_PSDDR} + 0.150	10	-0.1		
LPDDR4	0.000	V _{REF} - 0.100	V _{REF} + 0.100	V _{CCO_PSDDR}	0.3 x V _{CCO_PSDDR} - 0.150	0.3 x V _{CCO_PSDDR} + 0.150	0.1	-10		
DDR3	-0.300	V _{REF} - 0.100	V _{REF} + 0.100	V _{CCO_PSDDR}	0.5 x V _{CCO_PSDDR} - 0.175	0.5 x V _{CCO_PSDDR} + 0.175	8	-8		
LPDDR3	0.000	V _{REF} - 0.100	V _{REF} + 0.100	V _{CCO_PSDDR}	0.5 x V _{CCO_PSDDR} - 0.150	0.5 x V _{CCO_PSDDR} + 0.150	8	-8		
DDR3L	-0.300	V _{REF} - 0.090	V _{REF} + 0.090	V _{CCO_PSDDR}	0.5 x V _{CCO_PSDDR} - 0.150	0.5 x V _{CCO_PSDDR} + 0.150	8	-8		

Notes:

- Tested according to relevant specifications.
- DDR4 V_{OL}/V_{OH} specifications are only applicable for DQ/DQS pins.

Table 19: Complementary Differential SelectIO DC Input and Output Levels for HP I/O Banks⁽¹⁾

I/O Standard	V _{ICM} (V) ⁽²⁾			V _{ID} (V) ⁽³⁾		V _{OL} (V) ⁽⁴⁾	V _{OH} (V) ⁽⁵⁾	I _{OL}	I _{OH}
	Min	Typ	Max	Min	Max	Max	Min	mA	mA
DIFF_HSTL_I	0.680	V _{CCO} /2	(V _{CCO} /2) + 0.150	0.100	–	0.400	V _{CCO} – 0.400	5.8	-5.8
DIFF_HSTL_I_12	0.400 × V _{CCO}	V _{CCO} /2	0.600 × V _{CCO}	0.100	–	0.250 × V _{CCO}	0.750 × V _{CCO}	4.1	-4.1
DIFF_HSTL_I_18	(V _{CCO} /2) – 0.175	V _{CCO} /2	(V _{CCO} /2) + 0.175	0.100	–	0.400	V _{CCO} – 0.400	6.2	-6.2
DIFF_HSUL_12	(V _{CCO} /2) – 0.120	V _{CCO} /2	(V _{CCO} /2) + 0.120	0.100	–	20% V _{CCO}	80% V _{CCO}	0.1	-0.1
DIFF_SSTL12	(V _{CCO} /2) – 0.150	V _{CCO} /2	(V _{CCO} /2) + 0.150	0.100	–	(V _{CCO} /2) – 0.150	(V _{CCO} /2) + 0.150	8.0	-8.0
DIFF_SSTL135	(V _{CCO} /2) – 0.150	V _{CCO} /2	(V _{CCO} /2) + 0.150	0.100	–	(V _{CCO} /2) – 0.150	(V _{CCO} /2) + 0.150	9.0	-9.0
DIFF_SSTL15	(V _{CCO} /2) – 0.175	V _{CCO} /2	(V _{CCO} /2) + 0.175	0.100	–	(V _{CCO} /2) – 0.175	(V _{CCO} /2) + 0.175	10.0	-10.0
DIFF_SSTL18_I	(V _{CCO} /2) – 0.175	V _{CCO} /2	(V _{CCO} /2) + 0.175	0.100	–	(V _{CCO} /2) – 0.470	(V _{CCO} /2) + 0.470	7.0	-7.0

Notes:

1. DIFF POD10 and DIFF POD12 HP I/O bank specifications are shown in Table 20, Table 21, and Table 22.
2. V_{ICM} is the input common mode voltage.
3. V_{ID} is the input differential voltage.
4. V_{OL} is the single-ended low-output voltage.
5. V_{OH} is the single-ended high-output voltage.

Table 20: DC Input Levels for Differential POD10 and POD12 I/O Standards⁽¹⁾⁽²⁾

I/O Standard	V _{ICM} (V)			V _{ID} (V)	
	Min	Typ	Max	Min	Max
DIFF_POD10	0.63	0.70	0.77	0.14	–
DIFF_POD12	0.76	0.84	0.92	0.16	–

Notes:

1. Tested according to relevant specifications.
2. Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).

Table 21: DC Output Levels for Single-ended and Differential POD10 and POD12 Standards⁽¹⁾⁽²⁾

Symbol	Description	V _{OUT}	Min	Typ	Max	Units
R _{OL}	Pull-down resistance.	V _{OM_DC} (as described in Table 22)	36	40	44	Ω
R _{OH}	Pull-up resistance.	V _{OM_DC} (as described in Table 22)	36	40	44	Ω

Notes:

1. Tested according to relevant specifications.
2. Standards specified using the default I/O standard configuration. For details, see the *UltraScale Architecture SelectIO Resources User Guide* ([UG571](#)).

Table 22: Table 21 Definitions for DC Output Levels for POD Standards

Symbol	Description	All Speed Grades	Units
V _{OM_DC}	DC output Mid measurement level (for IV curve linearity).	0.8 × V _{CCO}	V

PS Gigabit Ethernet Controller Interface

Table 44: RGMII Interface⁽¹⁾

Symbol	Description	Min	Max	Units
T _{DGEMTXCLK}	Transmit clock duty cycle.	45	55	%
T _{GEMTXCKO}	TXD output clock to out time.	-0.5	0.5	ns
T _{GEMRXDCK}	RXD input setup time.	0.8	—	ns
T _{GEMRXCKD}	RXD input hold time.	0.8	—	ns
T _{MdioCLK}	MDC output clock period.	400	—	ns
T _{MdioCKL}	MDC low time.	160	—	ns
T _{MdioCKH}	MDC high time.	160	—	ns
T _{MdiODCK}	MDIO input data setup time.	80	—	ns
T _{MdiOCKD}	MDIO input data hold time.	0.0	—	ns
T _{MdiOCKO}	MDIO output data delay time.	-1.0	15	ns
F _{GETXCLK}	RGMII_TX_CLK transmit clock frequency.	—	125	MHz
F _{GERXCLK}	RGMII_RX_CLK receive clock frequency.	—	125	MHz
F _{ENET_REF_CLK}	Ethernet reference clock frequency.	—	125	MHz

Notes:

1. The test conditions are configured to the LVCMS 2.5V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.

PS SD/SDIO Controller Interface

Table 45: SD/SDIO Interface⁽¹⁾

Symbol	Description	Min	Max	Units
SD/SDIO Interface DDR50 Mode				
T _{DCDDRCLK}	SD device clock duty cycle.	45	55	%
T _{SDDDRCK01}	Clock to output delay, data. ⁽²⁾	1.0	6.8	ns
T _{SDDRIVW}	Input valid data window. ⁽³⁾	3.5	—	ns
T _{SDDDRDCK2}	Input setup time, command.	4.7	—	ns
T _{SDDDRCKD2}	Input hold time, command.	1.5	—	ns
T _{SDDDRCK02}	Clock to output delay, command.	1.0	13.8	ns
F _{SDDDRCLK}	High-speed mode SD device clock frequency.	—	50	MHz
SD/SDIO Interface SDR104				
T _{DCSDHSCLK1}	SD device clock duty cycle.	40	60	%
T _{SdSDRCK01}	Clock to output delay, all outputs. ⁽²⁾	1.0	3.2	ns
T _{SdSDR1IVW}	Input valid data window. ⁽³⁾	0.5	—	UI
F _{SdSDRCLK1}	SDR104 mode device clock frequency.	—	200	MHz
SD/SDIO Interface SDR50/25				
T _{DCSDHSCLK2}	SD device clock duty cycle.	40	60	%
T _{SdSDRCK02}	Clock to output delay, all outputs. ⁽²⁾	1.0	6.8	ns
T _{SdSDR2IVW}	Input valid data window. ⁽³⁾	0.3	—	UI

Table 45: SD/SDIO Interface⁽¹⁾ (Cont'd)

Symbol	Description	Min	Max	Units
$F_{SDSDRCLK2}$	SDR50 mode device clock frequency.	–	100	MHz
	SDR25 mode device clock frequency.	–	50	MHz
SD/SDIO Interface SDR12				
$T_{DCSDHSCLK3}$	SD device clock duty cycle.	40	60	%
$T_{SDSDRCKO3}$	Clock to output delay, all outputs.	1.0	36.8	ns
$T_{SDSDRCK3}$	Input setup time, all inputs.	24.0	–	ns
$T_{SDSDRCKD3}$	Input hold time, all inputs.	1.5	–	ns
$F_{SDSDRCLK3}$	SDR12 mode device clock frequency.	–	25	MHz
SD/SDIO Interface High-Speed Mode				
$T_{DCSDHSCLK}$	SD device clock duty cycle.	47	53	%
$T_{SDHSCKO}$	Clock to output delay, all outputs. ⁽²⁾	2.2	13.8	ns
$T_{SDHSDIVW}$	Input valid data window. ⁽³⁾	0.35	–	UI
$F_{SDHSCLK}$	High-speed mode SD device clock frequency.	–	50	MHz
SD/SDIO Interface Standard Mode				
$T_{DCSDSCLK}$	SD device clock duty cycle.	45	55	%
T_{SDSCKO}	Clock to output delay, all outputs.	–2.0	4.5	ns
T_{SDSDCK}	Input setup time, all inputs.	2.0	–	ns
T_{SDSCKD}	Input hold time, all inputs.	2.0	–	ns
$F_{SDIDCLK}$	Clock frequency in identification mode.	–	400	KHz
F_{SDSCLK}	Standard SD device clock frequency.	–	19	MHz

Notes:

1. The test conditions SD/SDIO standard mode (default speed mode) use an 8 mA drive strength, fast slew rate, and a 30 pF load. For SD/SDIO high-speed mode, the test conditions use a 12 mA drive strength, fast slew rate, and a 30 pF load. For other SD/SDIO modes, the test conditions use a 12 mA drive strength, fast slew rate, and a 15 pF load.
2. This specification is achieved using pre-determined DLL tuning.
3. This specification is required for capturing input data using DLL tuning.

PS eMMC Standard Interface

Table 46: eMMC Standard Interface⁽¹⁾

Symbol	Description	Min	Max	Units
eMMC Standard Interface				
T _{DCEMMCHSCLK}	eMMC clock duty cycle.	45	55	%
T _{E姚MCHSCKO}	Clock to output delay, all outputs.	-2.0	4.5	ns
T _{E姚MCHSDCK}	Input setup time, all inputs.	2.0	-	ns
T _{E姚MCHSCKD}	Input hold time, all inputs.	2.0	-	ns
F _{E姚MCHSCLK}	eMMC clock frequency.	-	25	MHz
eMMC High-Speed SDR Interface				
T _{DCEMMCHSCLK}	eMMC high-speed SDR clock duty cycle.	45	55	%
T _{E姚MCHSCKO}	Clock to output delay, all outputs. ⁽²⁾	3.2	16.8	ns
T _{E姚MCHSDIVW}	Input valid data window. ⁽³⁾	0.4	-	UI
F _{E姚MCHSCLK}	eMMC high speed SDR clock frequency.	-	50	MHz
eMMC High-Speed DDR Interface				
T _{DCEMMCDRCLK}	eMMC high-speed DDR clock duty cycle.	45	55	%
T _{E姚MCDRSCKO1}	Data clock to output delay. ⁽²⁾	2.7	7.3	ns
T _{E姚MCSDRIVW}	Input valid data window. ⁽³⁾	3.5	-	ns
T _{E姚MCDDRCKO2}	Command clock to output delay.	3.2	16	ns
T _{E姚MCDDRCK2}	Command input setup time.	3.9	-	ns
T _{E姚MCDDRCKD2}	Command input hold time.	2.5	-	ns
F _{E姚MCDDRCLK}	eMMC high-speed DDR clock frequency.	-	50	MHz
eMMC HS200 Interface				
T _{DCEMMCHS200CLK}	eMMC HS200 clock duty cycle.	40	60	%
T _{E姚MCHS200CKO}	Clock to output delay, all outputs. ⁽²⁾	1.0	3.4	ns
T _{E姚MCSDRIVW}	Input valid data window. ⁽³⁾	0.4	-	UI
F _{E姚MCHS200CLK}	eMMC HS200 clock frequency.	-	200	MHz

Notes:

1. The test conditions for eMMC standard mode use an 8 mA drive strength, fast slew rate, and a 30 pF load. For eMMC high-speed mode, the test conditions use a 12 mA drive strength, fast slew rate, and a 30 pF load. For other eMMC modes, the test conditions use a 12 mA drive strength, fast slew rate, and a 15 pF load.
2. This specification is achieved using pre-determined DLL tuning.
3. This specification is required for capturing input data using DLL tuning.

PS SPI Controller Interface

Table 48: SPI Interfaces⁽¹⁾

Symbol	Description	Min	Max	Units
SPI Master Interface				
T _{DCMSPICLK}	SPI master mode clock duty cycle.	45	55	%
T _{MSPISSCLK}	Slave select asserted to first active clock edge.	1 ⁽²⁾	–	F _{SPI_REF_CLK} cycles
T _{MSPISCLKSS}	Last active clock edge to slave select deasserted.	1 ⁽²⁾	–	F _{SPI_REF_CLK} cycles
T _{MSPIDCK}	Input setup time for MISO.	–2.0	–	ns
T _{MSPICKD}	Input hold time for MISO.	0.3	–	F _{MSPICLK} cycles
T _{MSPICKO}	MOSI and slave select clock to out delay.	–2.0	5.0	ns
F _{MSPICLK}	SPI master device clock frequency.	–	50	MHz
F _{SPI_REF_CLK}	SPI reference clock frequency.	–	200	MHz
SPI Slave Interface				
T _{SPPISSCLK}	Slave select asserted to first active clock edge.	2	–	F _{SPI_REF_CLK} cycles
T _{SPPISCLKSS}	Last active clock edge to slave select deasserted.	2	–	F _{SPI_REF_CLK} cycles
T _{SPPIDCK}	Input setup time for MOSI.	5.0	–	ns
T _{SPPICKD}	Input hold time for MOSI.	1	–	F _{SPI_REF_CLK} cycles
T _{SPPICKO}	MISO clock to out delay.	0.0	13.0	ns
F _{SPPICLK}	SPI slave mode device clock frequency.	–	25	MHz
F _{SPI_REF_CLK}	SPI reference clock frequency.	–	200	MHz

Notes:

1. The test conditions are configured to the LVC MOS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 30 pF load.
2. Valid when two SPI_REF_CLK delays are programmed between CS and CLK for T_{MSPISSCLK}, and between CLK and CS for T_{MSPISCLKSS} in the SPI delay_reg0 register.

PS CAN Controller Interface

Table 49: CAN Interface⁽¹⁾

Symbol	Description	Min	Max	Units
T _{PWCANRX}	Receive pulse width.	1.0	–	μs
T _{PWCANTX}	Transmit pulse width.	1.0	–	μs
F _{CAN_REF_CLK}	Internally sourced CAN reference clock frequency.	–	100	MHz
	Externally sourced CAN reference clock frequency.	–	40	MHz

Notes:

1. The test conditions are configured to the LVC MOS 3.3V I/O standard with a 12 mA drive strength, fast slew rate, and a 15 pF load.

PS-GTR Transceiver

Table 56: PS-GTR Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
D _{VPPIN}	Differential peak-to-peak input voltage (external AC coupled).		100	—	1200	mV
V _{IN}	Single-ended input voltage. Voltage measured at the pin referenced to GND.		75	—	V _{PS_MGTRAVCC}	mV
V _{CMIN}	Common mode input voltage.		—	0	—	mV
D _{VPPOUT}	Differential peak-to-peak output voltage. ⁽¹⁾	Transmitter output swing is set to maximum value.	800	—	—	mV
V _{CMOUTAC}	Common mode output voltage: AC coupled (equation based).		V _{PS_MGTRAVCC} – D _{VPPOUT} /2			mV
R _{IN}	Differential input resistance.		—	100	—	Ω
R _{OUT}	Differential output resistance.		—	100	—	Ω
R _{MGTRREF}	Resistor value between calibration resistor pin to GND.		497.5	500	502.5	Ω
T _{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew (All packages).		—	—	20	ps
C _{EXT}	Recommended external AC coupling capacitor. ⁽²⁾		—	100	—	nF

Notes:

1. The output swing and pre-emphasis levels are programmable using the attributes discussed in the *Zynq UltraScale+ MPSoC Technical Reference Manual* (UG1085), and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

Table 57: PS-GTR Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V _{IDIFF}	Differential peak-to-peak input voltage.	250	—	2000	mV
R _{IN}	Differential input resistance.	—	100	—	Ω
C _{EXT}	Required external AC coupling capacitor.	—	10	—	nF

Table 58: PS-GTR Transceiver Performance

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
F _{GTRMAX}	PS-GTR maximum line rate.	6.0	6.0	6.0	Gb/s
F _{GTRMIN}	PS-GTR minimum line rate.	1.25	1.25	1.25	Gb/s

Table 59: PS-GTR Transceiver PLL/Lock Time Adaptation

Symbol	Description	Min	Typ	Max	Units
T _{LOCK}	Initial PLL lock.	—	—	0.11	ms
T _{DLOCK}	Clock recovery phase acquisition and adaptation time.	—	—	24 × 10 ⁶	UI

Table 63: PS-GTR Transceiver Receiver Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F _{GTRRX}	Serial data rate.		1.25	–	6	Gb/s
RX _{SST}	Receiver spread-spectrum tracking.	Modulated at 33 KHz	–5000	–	0	ppm
RX _{PPMTOL}	Data/REFCLK PPM offset tolerance.	All data rates	–350	–	350	ppm

Table 64: PCI Express Protocol Characteristics (PS-GTR Transceivers)⁽¹⁾

Standard	Description	Line Rate (Mb/s)	Min	Max	Units
PCI Express Transmitter Jitter Generation					
PCI Express Gen 1	Total transmitter jitter.	2500	–	0.25	UI
PCI Express Gen 2	Total transmitter jitter.	5000	–	0.25	UI
PCI Express Receiver High Frequency Jitter Tolerance					
PCI Express Gen 1	Total receiver jitter tolerance.	2500	0.65	–	UI
PCI Express Gen 2 ⁽²⁾	Receiver inherent timing error.	5000	0.4	–	UI
	Receiver inherent deterministic timing error.	5000	0.3	–	UI

Notes:

1. Tested per card electromechanical (CEM) methodology.
2. Between 1 MHz and 10 MHz the minimum sinusoidal jitter roll-off with a slope of 20 dB/decade.

Table 65: Serial ATA (SATA) Protocol Characteristics (PS-GTR Transceivers)

Standard	Description	Line Rate (Mb/s)	Min	Max	Units
Serial ATA Transmitter Jitter Generation					
SATA Gen 1	Total transmitter jitter.	1500	–	0.37	UI
SATA Gen 2	Total transmitter jitter.	3000	–	0.37	UI
SATA Gen 3	Total transmitter jitter.	6000	–	0.52	UI
Serial ATA Receiver High Frequency Jitter Tolerance					
SATA Gen 1	Total receiver jitter tolerance.	1500	0.27	–	UI
SATA Gen 2	Total receiver jitter tolerance.	3000	0.27	–	UI
SATA Gen 2	Total receiver jitter tolerance.	6000	0.16	–	UI

Table 66: DisplayPort Protocol Characteristics (PS-GTR Transceivers)⁽¹⁾

Standard	Description	Line Rate (Mb/s)	Min	Max	Units
DisplayPort Transmitter Jitter Generation					
RBR	Total transmitter jitter.	1620	–	0.42	UI
HBR	Total transmitter jitter.	2700	–	0.42	UI
HBR2 D10.2	Total transmitter jitter.	5400	–	0.40	UI
HBR2 CPAT	Total transmitter jitter.	5400	–	0.58	UI

Notes:

1. Only the transmitter is supported.

Input Delay Measurement Methodology

Table 78 shows the test setup parameters used for measuring input delay.

Table 78: Input Delay Measurement Methodology

Description	I/O Standard Attribute	$V_L^{(1)(2)}$	$V_H^{(1)(2)}$	$V_{MEAS}^{(1)(4)(6)}$	$V_{REF}^{(1)(3)(5)}$
LVCMS, 1.2V	LVCMS12	0.1	1.1	0.6	—
LVCMS, LVDCI, HSLVDCI, 1.5V	LVCMS15, LVDCI_15, HSLVDCI_15	0.1	1.4	0.75	—
LVCMS, LVDCI, HSLVDCI, 1.8V	LVCMS18, LVDCI_18, HSLVDCI_18	0.1	1.7	0.9	—
LVCMS, 2.5V	LVCMS25	0.1	2.4	1.25	—
LVCMS, 3.3V	LVCMS33	0.1	3.2	1.65	—
LVTTL, 3.3V	LVTTL	0.1	3.2	1.65	—
HSTL (high-speed transceiver logic), class I, 1.2V	HSTL_I_12	$V_{REF} - 0.25$	$V_{REF} + 0.25$	V_{REF}	0.6
HSTL, class I, 1.5V	HSTL_I	$V_{REF} - 0.325$	$V_{REF} + 0.325$	V_{REF}	0.75
HSTL, class I, 1.8V	HSTL_I_18	$V_{REF} - 0.4$	$V_{REF} + 0.4$	V_{REF}	0.9
HSUL (high-speed unterminated logic), 1.2V	HSUL_12	$V_{REF} - 0.25$	$V_{REF} + 0.25$	V_{REF}	0.6
SSTL12 (stub series terminated logic), 1.2V	SSTL12	$V_{REF} - 0.25$	$V_{REF} + 0.25$	V_{REF}	0.6
SSTL135 and SSTL135 class II, 1.35V	SSTL135, SSTL135_II	$V_{REF} - 0.2875$	$V_{REF} + 0.2875$	V_{REF}	0.675
SSTL15 and SSTL15 class II, 1.5V	SSTL15, SSTL15_II	$V_{REF} - 0.325$	$V_{REF} + 0.325$	V_{REF}	0.75
SSTL18, class I and II, 1.8V	SSTL18_I, SSTL18_II	$V_{REF} - 0.4$	$V_{REF} + 0.4$	V_{REF}	0.9
POD10, 1.0V	POD10	$V_{REF} - 0.2$	$V_{REF} + 0.2$	V_{REF}	0.7
POD12, 1.2V	POD12	$V_{REF} - 0.24$	$V_{REF} + 0.24$	V_{REF}	0.84
DIFF_HSTL, class I, 1.2V	DIFF_HSTL_I_12	0.6 – 0.25	0.6 + 0.25	0 ⁽⁶⁾	—
DIFF_HSTL, class I, 1.5V	DIFF_HSTL_I	0.75 – 0.325	0.75 + 0.325	0 ⁽⁶⁾	—
DIFF_HSTL, class I, 1.8V	DIFF_HSTL_I_18	0.9 – 0.4	0.9 + 0.4	0 ⁽⁶⁾	—
DIFF_HSUL, 1.2V	DIFF_HSUL_12	0.6 – 0.25	0.6 + 0.25	0 ⁽⁶⁾	—
DIFF_SSTL, 1.2V	DIFF_SSTL12	0.6 – 0.25	0.6 + 0.25	0 ⁽⁶⁾	—
DIFF_SSTL135 and DIFF_SSTL135 class II, 1.35V	DIFF_SSTL135, DIFF_SSTL135_II	0.675 – 0.2875	0.675 + 0.2875	0 ⁽⁶⁾	—
DIFF_SSTL15 and DIFF_SSTL15 class II, 1.5V	DIFF_SSTL15, DIFF_SSTL15_II	0.75 – 0.325	0.75 + 0.325	0 ⁽⁶⁾	—
DIFF_SSTL18_I, DIFF_SSTL18_II, 1.8V	DIFF_SSTL18_I, DIFF_SSTL18_II	0.9 – 0.4	0.9 + 0.4	0 ⁽⁶⁾	—
DIFF_POD10, 1.0V	DIFF_POD10	0.5 – 0.2	0.5 + 0.2	0 ⁽⁶⁾	—
DIFF_POD12, 1.2V	DIFF_POD12	0.6 – 0.25	0.6 + 0.25	0 ⁽⁶⁾	—
LVDS (low-voltage differential signaling), 1.8V	LVDS	0.9 – 0.125	0.9 + 0.125	0 ⁽⁶⁾	—
LVDS_25, 2.5V	LVDS_25	1.25 – 0.125	1.25 + 0.125	0 ⁽⁶⁾	—

Device Pin-to-Pin Output Parameter Guidelines

The pin-to-pin numbers in [Table 87](#) through [Table 89](#) are based on the clock root placement in the center of the device. The actual pin-to-pin values will vary if the root placement selected is different. Consult the Vivado Design Suite timing report for the actual pin-to-pin values.

Table 87: Global Clock Input to Output Delay Without MMCM (Near Clock Region)

Symbol	Description	Device	Speed Grade and V_{CCINT} Operating Voltages					Units	
			0.90V	0.85V		0.72V			
			-3	-2	-1	-2	-1		
SSTL15 Global Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, without MMCM.									
TICKOF	Global clock input and output flip-flop <i>without</i> MMCM (near clock region).	XCZU2	N/A	4.90	5.28	5.35	5.61	ns	
		XCZU3	N/A	4.90	5.28	5.35	5.61	ns	
		XCZU4	4.89	5.83	6.36	6.00	6.79	ns	
		XCZU5	4.89	5.83	6.36	6.00	6.79	ns	
		XCZU6	5.00	5.91	6.35	6.66	7.09	ns	
		XCZU7	5.39	6.54	7.01	7.16	7.62	ns	
		XCZU9	5.00	5.91	6.35	6.66	7.09	ns	
		XCZU11	5.82	6.96	7.61	7.19	8.36	ns	
		XCZU15	5.15	6.09	6.55	6.90	7.38	ns	
		XCZU17	5.72	6.90	7.40	7.62	8.07	ns	
		XCZU19	5.72	6.90	7.40	7.62	8.07	ns	

Notes:

1. This table lists representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible I/O and CLB flip-flops are clocked by the global clock net.

GTH Transceiver Specifications

The *UltraScale Architecture and Product Overview* ([DS890](#)) lists the Zynq UltraScale+ MPSoCs that include the GTH transceivers.

GTH Transceiver DC Input and Output Levels

Table 94 summarizes the DC specifications of the GTH transceivers in Zynq UltraScale+ MPSoC. Consult the *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)) for further details.

Table 94: GTH Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV _{PPIN}	Differential peak-to-peak input voltage (external AC coupled).	> 10.3125 Gb/s	150	—	1250	mV
		6.6 Gb/s to 10.3125 Gb/s	150	—	1250	mV
		≤ 6.6 Gb/s	150	—	2000	mV
V _{IN}	Single-ended input voltage. Voltage measured at the pin referenced to GND.	DC coupled V _{MGTAVTT} = 1.2V	-400	—	V _{MGTAVTT}	mV
V _{CMIN}	Common mode input voltage.	DC coupled V _{MGTAVTT} = 1.2V	—	2/3 V _{MGTAVTT}	—	mV
D _{VPPOUT}	Differential peak-to-peak output voltage. ⁽¹⁾	Transmitter output swing is set to 11111	800	—	—	mV
V _{CMOUTDC}	Common mode output voltage: DC coupled (equation based).	When remote RX is terminated to GND	V _{MGTAVTT} /2 - D _{VPPOUT} /4			mV
		When remote RX termination is floating	V _{MGTAVTT} - D _{VPPOUT} /2			mV
		When remote RX is terminated to V _{RX_TERM} ⁽²⁾	V _{MGTAVTT} - $\frac{D_{VPPOUT}}{4} - \left(\frac{V_{MGTAVTT} - V_{RX_TERM}}{2} \right)$			mV
V _{CMOUTAC}	Common mode output voltage: AC coupled (equation based).	V _{MGTAVTT} - D _{VPPOUT} /2			—	mV
R _{IN}	Differential input resistance.	—	100	—	—	Ω
R _{OUT}	Differential output resistance.	—	100	—	—	Ω
T _{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew (all packages).	—	—	10	—	ps
C _{EXT}	Recommended external AC coupling capacitor. ⁽³⁾	—	100	—	—	nF

Notes:

1. The output swing and pre-emphasis levels are programmable using the attributes discussed in the *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)), and can result in values lower than reported in this table.
2. V_{RX_TERM} is the remote RX termination voltage.
3. Other values can be used as appropriate to conform to specific protocols and standards.

Table 103: GTH Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F _{GTHTX}	Serial data rate range		0.500	–	F _{GTHMAX}	Gb/s
T _{RTX}	TX rise time	20%–80%	–	21	–	ps
T _{FTX}	TX fall time	80%–20%	–	21	–	ps
T _{LLSKEW}	TX lane-to-lane skew ⁽¹⁾		–	–	500.00	ps
T _{J16.375}	Total jitter ⁽²⁾⁽⁴⁾	16.375 Gb/s	–	–	0.28	UI
D _{J16.375}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J15.0}	Total jitter ⁽²⁾⁽⁴⁾	15.0 Gb/s	–	–	0.28	UI
D _{J15.0}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J14.1}	Total jitter ⁽²⁾⁽⁴⁾	14.1 Gb/s	–	–	0.28	UI
D _{J14.1}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J14.1}	Total jitter ⁽²⁾⁽⁴⁾	14.025 Gb/s	–	–	0.28	UI
D _{J14.1}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J13.1}	Total jitter ⁽²⁾⁽⁴⁾	13.1 Gb/s	–	–	0.28	UI
D _{J13.1}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J12.5_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	12.5 Gb/s	–	–	0.28	UI
D _{J12.5_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J12.5_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	12.5 Gb/s	–	–	0.33	UI
D _{J12.5_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
T _{J11.3_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	11.3 Gb/s	–	–	0.28	UI
D _{J11.3_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J10.3125_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	10.3125 Gb/s	–	–	0.28	UI
D _{J10.3125_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J10.3125_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	10.3125 Gb/s	–	–	0.33	UI
D _{J10.3125_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
T _{J9.953_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	9.953 Gb/s	–	–	0.28	UI
D _{J9.953_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
T _{J9.953_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	9.953 Gb/s	–	–	0.33	UI
D _{J9.953_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
T _{J8.0}	Total jitter ⁽³⁾⁽⁴⁾	8.0 Gb/s	–	–	0.32	UI
D _{J8.0}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
T _{J6.6}	Total jitter ⁽³⁾⁽⁴⁾	6.6 Gb/s	–	–	0.30	UI
D _{J6.6}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.15	UI
T _{J5.0}	Total jitter ⁽³⁾⁽⁴⁾	5.0 Gb/s	–	–	0.30	UI
D _{J5.0}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.15	UI
T _{J4.25}	Total jitter ⁽³⁾⁽⁴⁾	4.25 Gb/s	–	–	0.30	UI
D _{J4.25}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.15	UI
T _{J4.0}	Total jitter ⁽³⁾⁽⁴⁾	4.0 Gb/s	–	–	0.32	UI
D _{J4.0}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.16	UI
T _{J3.20}	Total jitter ⁽³⁾⁽⁴⁾	3.20 Gb/s ⁽⁵⁾	–	–	0.20	UI
D _{J3.20}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.10	UI

Table 104: GTH Transceiver Receiver Switching Characteristics (Cont'd)

Symbol	Description	Condition	Min	Typ	Max	Units
J _T _SJ2.5	Sinusoidal jitter (CPLL) ⁽³⁾	2.5 Gb/s ⁽⁵⁾	0.30	—	—	UI
J _T _SJ1.25	Sinusoidal jitter (CPLL) ⁽³⁾	1.25 Gb/s ⁽⁶⁾	0.30	—	—	UI
J _T _SJ500	Sinusoidal jitter (CPLL) ⁽³⁾	500 Mb/s ⁽⁷⁾	0.30	—	—	UI
SJ Jitter Tolerance with Stressed Eye⁽²⁾						
J _T _TJSE3.2	Total jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.70	—	—	UI
J _T _TJSE6.6		6.6 Gb/s	0.70	—	—	UI
J _T _SJSE3.2	Sinusoidal jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.10	—	—	UI
J _T _SJSE6.6		6.6 Gb/s	0.10	—	—	UI

Notes:

1. Using RXOUT_DIV = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of 10^{-12} .
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. CPLL frequency at 3.2 GHz and RXOUT_DIV = 2.
5. CPLL frequency at 2.5 GHz and RXOUT_DIV = 2.
6. CPLL frequency at 2.5 GHz and RXOUT_DIV = 4.
7. CPLL frequency at 2.0 GHz and RXOUT_DIV = 8.
8. Composite jitter with RX equalizer enabled. DFE disabled.

GTH Transceiver Electrical Compliance

The *UltraScale Architecture GTH Transceiver User Guide* ([UG576](#)) contains recommended use modes that ensure compliance for the protocols listed in [Table 105](#). The transceiver wizard provides the recommended settings for those use cases and for protocol specific characteristics.

Table 115: GTY Transceiver Transmitter Switching Characteristics (Cont'd)

Symbol	Description	Condition	Min	Typ	Max	Units
T _{J3.20}	Total jitter ⁽³⁾⁽⁴⁾	3.20 Gb/s ⁽⁵⁾	–	–	0.20	UI
D _{J3.20}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.10	UI
T _{J2.5}	Total jitter ⁽³⁾⁽⁴⁾	2.5 Gb/s ⁽⁶⁾	–	–	0.20	UI
D _{J2.5}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.10	UI
T _{J1.25}	Total jitter ⁽³⁾⁽⁴⁾	1.25 Gb/s ⁽⁷⁾	–	–	0.15	UI
D _{J1.25}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.06	UI
T _{J500}	Total jitter ⁽³⁾⁽⁴⁾	500 Mb/s ⁽⁸⁾	–	–	0.10	UI
D _{J500}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.03	UI

Notes:

1. Using same REFCLK input with TX phase alignment enabled for up to four consecutive transmitters (one fully populated GTY Quad) at maximum line rate.
2. Using QPLL_FBDIV = 40, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. Using CPLL_FBDIV = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
4. All jitter values are based on a bit-error ratio of 10^{-12} .
5. CPLL frequency at 3.2 GHz and TXOUT_DIV = 2.
6. CPLL frequency at 2.5 GHz and TXOUT_DIV = 2.
7. CPLL frequency at 2.5 GHz and TXOUT_DIV = 4.
8. CPLL frequency at 2.0 GHz and TXOUT_DIV = 8.

Table 117: GTY Transceiver Protocol List (Cont'd)

Protocol	Specification	Serial Rate (Gb/s)	Electrical Compliance
Serial RapidIO	RapidIO specification 3.1	1.25–10.3125	Compliant
DisplayPort	DP 1.2B CTS	1.62–5.4	Compliant ⁽³⁾
Fibre channel	FC-PI-4	1.0625–14.025	Compliant
SATA Gen1, 2, 3	Serial ATA revision 3.0 specification	1.5, 3.0, and 6.0	Compliant
SAS Gen1, 2, 3	T10/BSR INCITS 519	3.0, 6.0, and 12.0	Compliant
SFI-5	OIF-SFI5-01.0	0.625 - 12.5	Compliant
Aurora	CEI-6G, CEI-11G-LR	All rates	Compliant

Notes:

1. 25 dB loss at Nyquist without FEC.
2. The transition time of the transmitter is faster than the IEEE Std 802.3-2012 specification.
3. This protocol requires external circuitry to achieve compliance.

Date	Version	Description of Revisions
02/10/2017	1.2	<p>Updated some of the maximum voltages in the Processor System (PS) section and other specifications in the Programmable Logic (PL) and GTH or GTY Transceiver sections of Table 1. Updated Table 2, Table 4, Table 6, Table 7, and Table 9. Revised the Power Supply Sequencing section including Table 10. Added PS and VCU ramp times to Table 11. Revised V_{ODIFF} in Table 24. Updated Table 25. Added Note 1 to Table 26. Table 30 replaces the previous three PS memory performance tables. Added values to Table 34, Table 37, and Table 38. Deleted the waveforms in the PS Switching Characteristics section (Figures 1-16 and Figures 25-26). Revised values in the PS NAND Memory Controller Interface section. Added and updated data in Table 40. Added Note 3 to Table 41. Added Note 3 to Table 42. Added Note 1 to Table 45. Updated Table 48 and removed Note 3. Added data to Table 56. Updated Table 60. Added Table 61. Updated Table 63. Revised Table 69. Added data to Table 70. Added Note 2 to Table 71. Updated Table 74 and added Note 4. Updated V_L and V_H values in Table 78. Added T_{MINPER_CLK}, revised F_{REFCLK}, and Note 1 to Table 82. Added $MMCM_F_{DPRCLK_MAX}$ to Table 85 and $PLL_F_{DPRCLK_MAX}$ to Table 86. Added data to Table 94, Table 96, Table 98, Table 101, and updated the note references in Table 102. Updated Table 103 and added Note 8. Updated Table 104 and added Note 7. Added more protocols, Note 1 and Note 2 to Table 105. Removed the GTH Transceiver Protocol Jitter Characteristics section because it is covered in Table 105. Added Note 1 to Table 109. Added data to Table 106, Table 108, Table 110, Table 113. Added Note 2 to Table 112. Added note references in Table 114. Updated Table 115 and added Note 8. Updated Table 116 and added Note 7. Added more protocols and Note 3 to Table 117. Removed the GTY Transceiver Protocol Jitter Characteristics section because it is covered in Table 117. Revised Table 124. Added T_{POR} and updated F_{ICAPCK} in Table 127. Updated the Automotive Applications Disclaimer.</p>
06/20/2016	1.1	<p>Updated the Summary description. In Table 1, revised V_{IN} for HP I/O banks and added clarifications to some descriptions and symbols. Added I_{RPU}, I_{RPD}, and Note 4 to Table 2 and updated $V_{PS_MGTRAVCC}$, the PL System Monitor section, and Note 3 and Note 5. Updated Note 5 in Table 4. Updated the PS Power-On/Off Power Supply Sequencing section including all the voltage supply names. Added MIPI_DPHY_DCI to Table 14, Table 15, and Table 17. Updated Table 23, including removing the V_{CCO} specification and adding Note 1. Added Note 1 to Table 24. Updated Table 25 speed specifications for Vivado Design Suite 2016.1. Added values to Table 28. Updated the -2 value in Table 29. Added $F_{DPLIVEVIDEO}$ and updated $F_{FCIDMACLK}$ in Table 33. Added VCO frequencies to Table 36. Added the T_{PSPOR} minimum to Table 37 and updated Note 1. Added Table 38. Added value delineation over V_{CCINT} operating voltages in Table 39. Revised values for F_{TCK} and T_{TAPTCK}/T_{TCKTAP} in Table 40 and added value delineation over V_{CCINT} operating voltages. Updated the PS NAND Memory Controller Interface section. Revised some units and Note 1 in Table 41 and Table 42. Removed Figure 6: Quad-SPI Interface (Feedback Clock Disabled) Timing. Updated Note 1 of Table 43. Added $F_{TSI_REF_CLK}$ to Table 44 and updated Note 1. In Table 45, revised $T_{DCSDHSCLK1}$, $T_{DCSDHSCLK2}$, and $T_{DCSDHSCLK3}$ and Note 1. In Table 46, revised Note 1. In Table 47, revised Note 1. Revised Table 48, including Note 1, and added Note 2 and Note 3. In Table 49, Table 50, Table 51, and Table 53, revised Note 1. Updated Table 71. Replaced Table 74. Updated Table 75 and Table 76. Updated Table 78 and Table 79. In Table 80, added the Block RAM and FIFO Clock-to-Out Delays section. Updated the R_{IN} and C_{EXT} values in Table 57 and Table 95. Updated the -2 (0.72V) and -1 (0.72V) values and added Note 1 to Table 97. Added Table 100 and Table 112. Added Note 2 to Table 106. Revised data in Table 109. Revised Table 114. Revised data and added notes in the Integrated Interface Block for Interlaken section and Table 121. Moved Table 123. Revised INL in Table 124. Added notes to Table 125 and Table 126. In the eFUSE and Programming Conditions table, updated the I_{PSFS} description.</p>
11/24/2015	1.0	Initial Xilinx release.